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Fault Characterization Through FPGAs Undervolting

Behzad Salami, Osman S. Unsal, and Adrian Cristal Kestelman

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Underscaling the supply voltage *below the nominal level* :

- Power/Energy Efficiency: Reduces quadratic ally dynamic and linearly static power.
- Reliability: Increases the circuit delay and in turn, causes timing faults.



Aggressive Undervolting is not DVFS!

Motivation



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Contribution of FPGAs in large data centers is growing, expected to be in <u>30%</u> of datacenter servers by 2020 (Top500 news).





Experimental Methodology



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- A Detailed study on <u>FPGA BRAMs</u>, which are a set of bitcells in the row-column format.
- **B** Experimental Methodology:
 - toell HW: Transfer content of BRAMs to ^{The mathematic series} 1. the host.
 - 2. <u>SW</u>: Analyze data, and adjust voltage of BRAMs.



Floorplan of VC707

Operating frequency is set to the maximum, i.e., ~500mhz.



Overall Behavior- Power & Reliability



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Fault Characterization at **CRITICAL** Region

Fault Variability between BRAMs

- BRAMs clustering using K-Mean clustering.
- Majority of BRAMs are low-vulnerable.
- ~36% of BRAMs never experience faults.
- Fully non-uniform fault distribution.



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VC707



KC705 VCCBRAM= Vcrash

* Different scales in y-axis * *Pattern= 18'h3FFFF *

Environmental Temperature

- **Methodology:** Adjusting environmental temperature, monitoring on-board temperature via PMBus.
- Experimental Observation:
 - At higher temperatures, fault rate is significantly reduced.
 - The <u>rate of this reduction</u> is highly platform-dependent (VC707 > KC705).
- Inverse Temperature Dependency (ITD):
 - For nano-scale technologies, under ultra low-voltage operations, the circuit delay reduces at higher temperatures since supply voltage approaches the threshold voltage.



* y-axis: VCCBRAM (V), y-axis: fault rate (per 1Mbit) *

Summary & Future Works



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Summary

- We <u>experimentally</u> showed how Xilinx FPGAs work under aggressive low-voltage operations.
- There is a <u>conservative voltage</u> <u>guardband</u> below the nominal level.
- BRAMs <u>power</u> is significantly reduced through Undervolting; however, <u>reliability</u> degrades below min safe voltage.
- We <u>characterized</u> the behavior of Undervolting faults at the critical region.

Future Works

- <u>Dynamic Vmin scaling</u>, adapted by frequency and temperature.
- More advanced designs, where other components such as <u>I/O</u>, <u>DDR</u>, <u>DSP</u> are undervolted.
- Efficient Fault Mitigation Techniques.
- <u>Profiling applications</u> such as Deep Neural Networks (DNNs), among others.
- Extending Undervolting for other commercial FPGAs such as <u>Intel/Altera.</u>



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Thanks!

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Contact: Behzad Salami behzad.salami@bsc.es

